











TPS2561A-Q1

ZHCSC59A - MARCH 2014-REVISED JUNE 2014

TPS2561A-Q1 双通道精密汽车用可调 限流电源开关

特性

- 符合 AEC-Q100
 - 器件人体模型 (HBM) 静电放电 (ESD) 分类等级 H2
 - 器件充电器件模型 (CDM) ESD 分类等级 C5
- 2个独立的电流限制通道
- 满足 USB 电流限制要求
- 可调电流限值, 250mA-2.8A (典型值)
- 精确的 2.1A (最小值) /2.5A (最大值) 设置
- 快速短路响应 3.5µs (典型值)
- 2 个 44mΩ 高侧金属氧化物半导体场效应晶体管 (MOSFET)
- 工作范围: 2.5V 至 6.5V
- 最大待机电源电流 2µA
- 内置软启动
- 15 kV/8kV 系统级静电放电 (ESD) 能力

2 应用范围 汽车 USB 充电端口

3 说明

TPS2561A-Q1是一款双通道配电开关,此开关用于对 电流限制精度有要求或者会遇到重电容负载和短路的汽 车应用。 这些器件通过一个外部电阻器为每个通道提 供一个 250mA 至 2.8A 之间(典型值)的可编程电流 限制阀值。对电源开关的上升和下降次数进行控制以 最大限度地降低接通/关闭期间的电流浪涌。

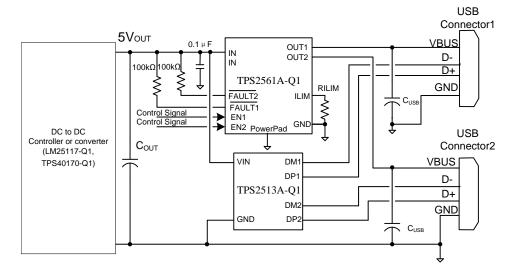
当输出负载超过电流限制阀值时,通过切换至恒定电流 模式, TPS2561A-Q1 器件的每个通道将输出电流限制 到一个安全水平上。 在过流和过热条件下,每个通道 的 FAULTx 逻辑输出单独置位为低电平。

与 TPS2511-Q 或 TPS2513A-Q1 一同使用,提供一个 低损耗,符合汽车应用需要,USB 充电端口解决方 案,此解决方案能够为目前普遍的手机和平板电脑充 电。

器件信息

部件号	封装	封装尺寸 (标称值)		
TPS2561A-Q1	SON (10)	3.00mm x 3.00mm		

作为双端口汽车 USB 充电端口解决方案的典型应用范围





14 机械封装和可订购信息 19

	目	录		
1	特性 1		9.1 Overview	9
2	应用范围1		9.2 Functional Block Diagram	9
3	说明1		9.3 Feature Description	9
4	修订历史记录		9.4 Device Functional Mode	10
5	Device Comparison Table	10	Application and Implementation	11
6	Pin Functions and Configurations		10.1 Application Information	11
7	Specifications4		10.2 Typical Application	11
	7.1 Absolute Maximum Ratings	11	Power Supply Requirements	17
	7.2 Handling Ratings	12	Layout	18
	7.3 Recommended Operating Conditions		12.1 Layout Guidelines	18
	7.4 Thermal Information		12.2 Layout Example	18
	7.5 Electrical Characteristics 5	13	器件和文档支持	19
	7.6 Typical Characteristics		13.1 商标	19
R	Parameter Measurement Information		13.2 静电放电警告	
a	Detailed Description9		13.3 Glossary	19
•	Detailed Description		In LEALNE TO JOSEPH CO.	4.0

4 修订历史记录

Cł	nanges from Original (March 2014) to Revision A	Page
•	已将特性从: 精确的 2.1A(最小值)/2.5A(最大值)设置(包括电阻器)更改为: 精确的 2.1A(最小值)/2.5A(最大值)设置	
•	Changed I _{OS} , Current-limit. to include additional R _{ILIM} values.	5
•	Changed Equation 1	11
•	Changed the Designing Above a Minimum Current Limit section	12
•	Changed the Designing Below a Maximum Current Limit section	13

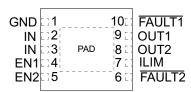


5 Device Comparison Table

DEVICE	MAXIMUM OPERATING CURRENT (A)	OUTPUTS	ENABLES	TYPICAL R _{DS(on)} (mΩ)	PACKAGE
TPS2556-Q1	5	1	Active-low	22	SON-8 (DRB)
TPS2557-Q1	5	1	Active-high	22	SON-8 (DRB)
TPS2561A-Q1	2.5	2	Active-high	44	SON-10 (DRC)

6 Pin Functions and Configurations

DRC PACKAGE (TOP VIEW)



Pin Functions

	PIN	1/0			
NAME	NAME NUMBER		DESCRIPTION		
EN1	4	ı	Enable input, logic high turns on channel one power switch		
EN2	5	I	Enable input, logic high turns on channel two power switch		
GND	1		Ground connection; connect externally to PowerPAD		
IN	2, 3	I	Input voltage; connect a 0.1 μF or greater ceramic capacitor from IN to GND as close to the IC as possible.		
FAULT1	10	0	Active-low open-drain output, asserted during overcurrent or overtemperature condition on channel one.		
FAULT2	6	0	Active-low open-drain output, asserted during overcurrent or overtemperature condition on channel two		
OUT1	9	0	Power-switch output for channel one		
OUT2	8	0	Power-switch output for channel two		
ILIM	7	0	External resistor used to set current-limit threshold; recommended 20 k Ω ≤ R_{ILIM} ≤ 187 k Ω .		
PowerPAD™	PAD		Internally connected to GND; used to heat-sink the part to the circuit board traces. Connect PowerPAD to GND pin externally.		



7 Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature range unless otherwise noted⁽¹⁾ (2)

		MIN	MAX	UNIT	
	Voltage range on IN, OUTx, ENx, ILIM, FAULTx	-0.3	7	V	
	Voltage range from IN to OUTx	-7	7	٧	
	Continuous output current	Internally			
	Continuous FAULTx sink current		25	mA	
	ILIM source current	Internally	Internally Limited		
TJ	Maximum junction temperature	-40	Internally Limited	°C	

⁽¹⁾ Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) Voltages are referenced to GND unless otherwise noted.

7.2 Handling Ratings

			MIN	MAX	UNIT
T _{STG}	Storage temperature range	-65	150	°C	
	Human Body Model (HBM)	AEC-Q100 Classification Level H2		2	kV
V _{ESD} (1)	Charged Device Model (CDM) AEC-Q100 Classification Level C5			750	٧
	System level (contact/air)		8/15 ⁽²⁾	kV	

Electrostatic discharge (ESD) to measure device sensitivity and immunity to damage caused by assembly line electrostatic discharges in to the device.

7.3 Recommended Operating Conditions

		MIN	MAX	UNIT	
V _{IN}	Input voltage, IN	2.5	6.5	V	
V_{ENx}	Enable voltage	0	6.5	٧	
V_{IH}	High-level input voltage on ENx	1.1		V	
V_{IL}	Low-level input voltage on ENx		0.66	V	
I_{OUTx}	Continuous output current per channel, OUTx	0	2.5	Α	
	Continuous FAULTx sink current	0	10	mA	
T_{J}	Operating junction temperature	-40	125	°C	
R _{ILIM}	Recommended resistor limit range	20	187	kΩ	

7.4 Thermal Information (1)

	THERMAL METRIC	TPS2561A-Q1	HAUT
	I HERMAL METRIC	DRC (10 TERMINALS)	UNIT
θ_{JA}	Junction-to-ambient thermal resistance	38.1	
θ_{JCtop}	Junction-to-case (top) thermal resistance	40.5	
θ_{JB}	Junction-to-board thermal resistance	13.6	°C/W
ΨЈТ	Junction-to-top characterization parameter	0.6	*C/vv
Ψ_{JB}	Junction-to-board characterization parameter	13.7	
θ_{JCbot}	Junction-to-case (bottom) thermal resistance	3.4	

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

⁽²⁾ Surges per EN61000-4-2, 1999 applied between USB connection for V_{BUS} and GND of the TPS2560EVM (HPA424, replacing TPS2560 with TPS2561A-Q1) evaluation module (documentation available on the Web.) These were the test level, no the failure threshold.



7.5 Electrical Characteristics

over recommended operating conditions, $V_{ENx} = V_{IN}$ (unless otherwise noted)

	PARAMETER		TEST COND	ITIONS ⁽¹⁾	MIN	TYP	MAX	UNIT
POWER S	SWITCH							
_	Static drain-source on-state	$T_J = 25^{\circ}C$				44	50	O
r _{DS(on)}	resistance per channel, IN to OUTx	–40°C ≤T _J ≤125 °C	-40°C ≤T _J ≤125 °C				70	mΩ
4	Dies time suitaut	V _{IN} = 6.5 V			1.5	3	4	
t _r	Rise time, output	V _{IN} = 2.5 V C _L	_x = 1 μF, R _{Lx} =	100 Ω,	0.5	2	3	
4	Fall time autout	V _{IN} = 6.5 V (se	ee Figure 9)		0.5	8.0	1.0	ms
t _f	Fall time, output	V _{IN} = 2.5 V			0.3	0.6	0.8	
ENABLE	INPUT EN							
	Enable pin turn on/off threshold				0.66		1.1	V
	Hysteresis					55 ⁽²⁾		mV
I _{EN}	Input current	V _{ENx} = 0 V or 6.5 V			-0.5		0.5	μΑ
t _{on}	Turnon time	$C_{Lx} = 1 \mu F, R_{Lx} = 100 \Omega$) (soo Figuro 0	1			9	ms
t_{off}	Turnoff time	$C_{Lx} = 1 \mu I$, $K_{Lx} = 100 \Omega$	z, (See Figure 9)			6	ms
CURREN	T LIMIT			_				
				$R_{ILIM} = 20 \text{ k}\Omega$	2560	2750	2980	
I _{os}	Current-limit (see Figure 11)	OUTx connected to GND		$R_{ILIM} = 24.3 \text{ k}\Omega$	2100	2250	2500	mA
				$R_{ILIM} = 61.9 \text{ k}\Omega$	800	900	1005	
				$R_{ILIM} = 100 \text{ k}\Omega$	470	560	645	
		OUT1 and OUT2 connected to GND		$R_{ILIM} = 47.5 \text{ k}\Omega$	2100	2300	2500	
t _{IOS}	Response time to short circuit	V _{IN} = 5 V (see Figure 1	0)			3.5 ⁽²⁾		μs
SUPPLY	CURRENT							
I _{IN(off)}	Supply current, low-level output	V _{IN} = 6.5 V, No load on	OUTx, $V_{ENx} =$	0 V		0.1	2.0	μΑ
I	Supply current, high-level output	V _{IN} = 6.5 V, No load on	OUT	$R_{ILIM} = 20 \text{ k}\Omega$		100	125	μΑ
I _{IN(on)}	Supply current, high-level output	VIN = 0.5 V, 140 load off	001	$R_{ILIM} = 100 \text{ k}\Omega$		85	110	μΑ
I_{REV}	Reverse leakage current	$V_{OUTx} = 6.5 \text{ V}, V_{IN} = 0 \text{ V}$	1	$T_J = 25^{\circ}C$		0.01	1.0	μΑ
UNDERV	OLTAGE LOCKOUT							
V_{UVLO}	Low-level input voltage, IN	V _{IN} rising				2.35	2.45	V
	Hysteresis, IN	$T_J = 25^{\circ}C$				35 ⁽²⁾		mV
FAULTX	FLAG							
V_{OL}	Output low voltage, FAULTx	I FAULTX = 1 mA					180	mV
	Off-state leakage	$V_{\overline{FAULTx}} = 6.5 V$					1	μΑ
	FAULTx deglitch	FAULTx assertion or de	e-assertion due	to overcurrent condition	6	9	13	ms
THERMA	L SHUTDOWN							
	Thermal shutdown threshold, OTSD2	2			155			°C
	Thermal shutdown threshold in current	nt-limit, OTSD			135			°C
	Hysteresis					20(2)		°C

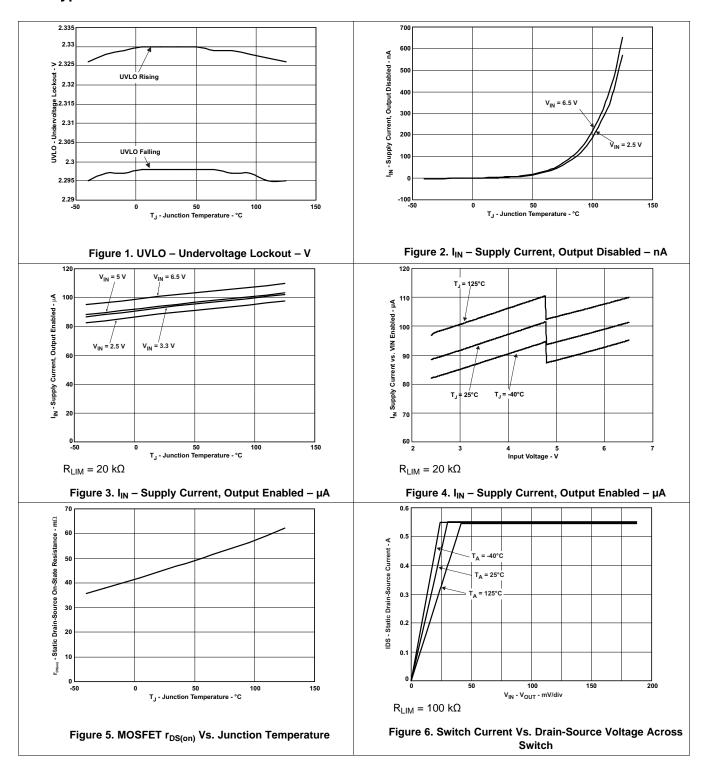
⁽¹⁾ Pulse-testing techniques maintain junction temperature close to ambient temperature; thermal effects must be taken into account

separately.

These parameters are provided for reference only, and do not constitute part of Tl's published specifications for purposes of Tl's product warranty.

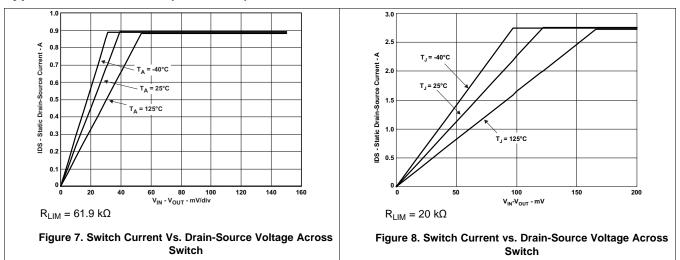


7.6 Typical Characteristics





Typical Characteristics (continued)



8 Parameter Measurement Information

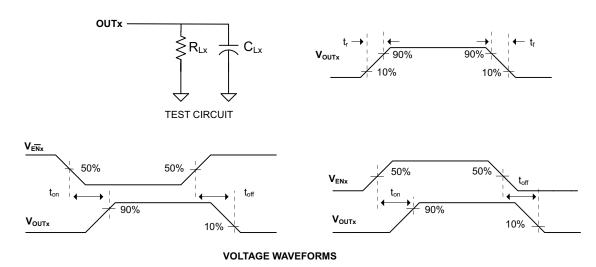


Figure 9. Test Circuit and Voltage Waveforms

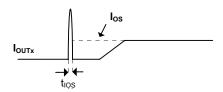


Figure 10. Response Time to Short Circuit Waveform



Parameter Measurement Information (continued)

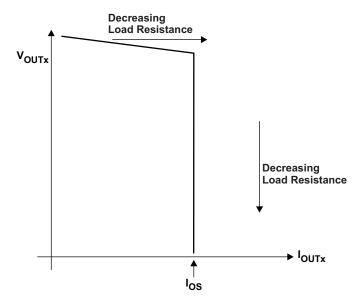


Figure 11. Output Voltage vs. Current-Limit Threshold

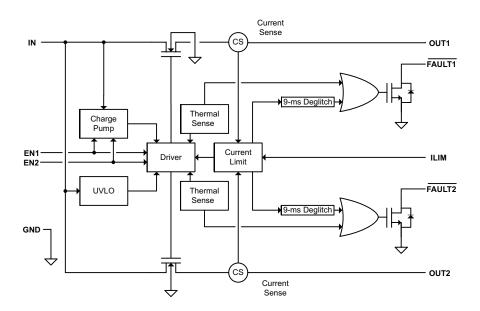


9 Detailed Description

9.1 Overview

The TPS2561A-Q1 is a dual-channel, current-limited power-distribution switch using N-channel MOSFETs for automotive applications where short circuits or heavy capacitive loads will be encountered. This device allows the user to program the current-limit threshold between 250 mA and 2.8 A (typ) per channel via an external resistor. This device incorporates an internal charge pump and gate drive circuitry necessary to drive the N-channel MOSFETs. The charge pump supplies power to the driver circuit for each channel and provides the necessary voltage to pull the gate of the MOSFET above the source. The charge pump operates from input voltages as low as 2.5 V and requires little supply current. The driver controls the gate voltage of the power switch. The driver incorporates circuitry that controls the rise and fall times of the output voltage to limit large current and voltage surges and provides built-in soft-start functionality. Each channel of the TPS2561A-Q1 limits the output current to the programmed current-limit threshold I_{OS} during an overcurrent or short-circuit event by reducing the charge pump voltage driving the N-channel MOSFET and operating it in the linear range of operation. The result of limiting the output current to I_{OS} reduces the output voltage at OUTx because the N-channel MOSFET is no longer fully enhanced.

9.2 Functional Block Diagram



9.3 Feature Description

9.3.1 Overcurrent Conditions

The TPS2561A-Q1 responds to overcurrent conditions by limiting the output current per channel to I_{OS}. When an overcurrent condition is detected, the device maintains a constant output current and reduces the output voltage accordingly. Two possible overload conditions can occur.

The first condition is when a short circuit or partial short circuit is present when the device is powered-up or enabled. The output voltage is held near zero potential with respect to ground and the TPS2561A-Q1 ramps the output current to I_{OS} . The TPS2561A-Q1 devices will limit the current to I_{OS} until the overload condition is removed or the device begins to thermal cycle.

The second condition is when a short circuit, partial short circuit, or transient overload occurs while the device is enabled and powered on. The device responds to the overcurrent condition within time t_{IOS} (see Figure 10). The current-sense amplifier is overdriven during this time and momentarily disables the internal current-limit MOSFET. The current-sense amplifier recovers and ramps the output current to I_{OS} . Similar to the previous case, the TPS2561A-Q1 will limit the current to I_{OS} until the overload condition is removed or the device begins to thermal cycle.



Feature Description (continued)

The TPS2561A-Q1 thermal cycles if an overload condition is present long enough to activate thermal limiting in any of the above cases. The device turns off when the junction temperature exceeds 135°C (min) while in current limit. The device remains off until the junction temperature cools 20°C (typ) and then restarts. The TPS2561A-Q1 cycles on/off until the overload is removed (see Figure 20).

9.3.2 FAULTx Response

The FAULTx open-drain outputs are asserted (active low) on an individual channel during an overcurrent or overtemperature condition. The TPS2561A-Q1 asserts the FAULTx signal until the fault condition is removed and the device resumes normal operation on that channel. The TPS2561A-Q1 is designed to eliminate false FAULTx reporting by using an internal delay "deglitch" circuit (9-ms typ) for overcurrent conditions without the need for external circuitry. This ensures that FAULTx is not accidentally asserted due to normal operation such as starting into a heavy capacitive load. The deglitch circuitry delays entering and leaving current-limited induced fault conditions. The FAULTx signal is not deglitched when the MOSFET is disabled due to an overtemperature condition but is deglitched after the device has cooled and begins to turn on. This unidrectional deglitch prevents FAULTx oscillation during an overtemperature event.

9.3.3 Thermal Sense

The TPS2561A-Q1 self protects by using two independent thermal sensing circuits that monitor the operating temperature of the power switch and disable operation if the temperature exceeds recommended operating conditions. Each channel of the TPS2561A-Q1 operates in constant-current mode during an overcurrent conditions, which increases the voltage drop across the power switch. The power dissipation in the package is proportional to the voltage drop across the power switch, which increases the junction temperature during an overcurrent condition. The first thermal sensor (OTSD) turns off the individual power switch channel when the die temperature exceeds 135°C (min) and the channel is in current limit. Hysteresis is built into the thermal sensor, and the switch turns on after the device has cooled approximately 20°C.

The TPS2561A-Q1 also has a second ambient thermal sensor (OTSD2). The ambient thermal sensor turns off both power switch channels when the die temperature exceeds 155°C (min) regardless of whether the power switch channels are in current limit and will turn on the power switches after the device has cooled approximately 20°C. The TPS2561A-Q1 continues to cycle off and on until the fault is removed.

9.4 Device Functional Mode

9.4.1 Undervoltage Lockout (UVLO)

The undervoltage lockout (UVLO) circuit disables the power switch until the input voltage reaches the UVLO turnon threshold. Built-in hysteresis prevents unwanted on/off cycling due to input voltage droop during turn on.

9.4.2 **Enable (ENx)**

The logic enables control the power switches and device supply current. The supply current is reduced to less than 2-µA when a logic low is present on ENx. A logic high input on ENx enables the driver, control circuits, and power switches. The enable inputs are compatible with both TTL and CMOS logic levels.



10 Application and Implementation

10.1 Application Information

The device is current-limited, power-distribution switch. It would limit the output current to IOS when short circuits or heavy capacitive loads are encountered.

10.2 Typical Application

10.2.1 Design Current Limit

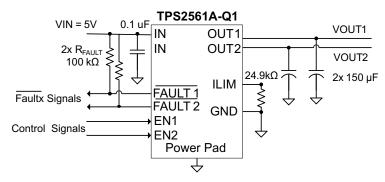


Figure 12. Typical Characteristics Reference Schematic

10.2.1.1 Design Requirements

For this design example, use the following as the input parameters.

DESIGN PARAMTER EXAMPLE VALUE

Input voltage 5V

Minimum current limit 2A

Maximum current limit 1A

Table 1. Design Parameters

10.2.1.2 Detailed Design Procedure

10.2.1.2.1 Determine Design Parameters

Beginning the design process requires deciding on a few parameters. The designer must know the following:

- Input voltage
- · Minimum current limit
- Maximum current limit

10.2.1.2.2 Programming the Current-Limit Threshold

The overcurrent threshold is user programmable via an external resistor, R_{ILIM} . R_{ILIM} sets the current-limit threshold for both channels. The TPS2561A-Q1 use an internal regulation loop to provide a regulated voltage on the ILIM pin. The current-limit threshold is proportional to the current sourced out of ILIM. The recommended 1% resistor range for R_{ILIM} is 20 k $\Omega \le R_{ILIM} \le 187$ k Ω to ensure stability of the internal regulation loop. Many applications require that the minimum current limit is above a certain current level or that the maximum current limit is below a certain current level, so it is important to consider the tolerance of the overcurrent threshold when selecting a value for R_{ILIM} . The following equations calculates the resulting overcurrent threshold for a given external resistor value (R_{ILIM}). The traces routing the R_{ILIM} resistor to the TPS2561A-Q1 should be as short as possible to reduce parasitic effects on the current-limit accuracy.



$$I_{OSmax}(mA) = \frac{49497V}{R_{(ILIM)}^{0.933}k\Omega} - 37$$

$$I_{OSnom}(mA) = \frac{53098V}{R_{(ILIM)}^{0.989}k\Omega}$$

$$I_{OSmin}(mA) = \frac{50576V}{R_{(ILIM)}^{0.987}k\Omega} - 64$$
(1)

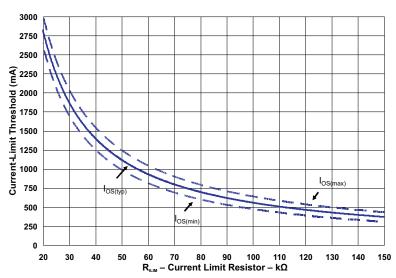


Figure 13. Current-Limit Threshold vs. R_{ILIM}

10.2.1.2.3 Designing Above a Minimum Current Limit

Some applications require that current limiting cannot occur below a certain threshold. For this example, assume that 2 A must be delivered to the load so that the minimum desired current-limit threshold is 2000 mA. Use the I_{OS} equations and Figure 13 to select R_{ILIM} .

$$I_{OSmin}(mA) = 2000 \text{ mA}$$

$$I_{OSmin}(mA) = \frac{50576V}{R_{(ILIM)}^{0.987}k\Omega} - 64$$

$$R_{\text{(ILIM)}}(k\Omega) = \left(\frac{50576}{I_{\text{OS(min)}} + 64}\right)^{\frac{1}{0.987}} = \left(\frac{50576}{2000 + 64}\right)^{\frac{1}{0.987}} = 25.56k\Omega$$
(2)

Select the closest 1% resistor less than the calculated value: R_{ILIM} = 25.5 k Ω . This sets the minimum current-limit threshold at 2005 mA .

$$I_{OSmin}(mA) = \frac{50576}{R_{(ILIM)}^{0.987} k\Omega} - 64 = \frac{50576}{(25.5)^{0.987}} - 64 = 2005 \text{ mA}$$
(3)

Use the I_{OS} equations, Figure 13, and the previously calculated value for R_{ILIM} to calculate the maximum resulting current-limit threshold at 2374 mA.

$$I_{OSmax}(mA) = \frac{49497}{R_{(ILIM)}^{0.933}} - 37 = \frac{49497}{(25.5)^{0.933}} - 37 = 2374 \text{ mA}$$
(4)



10.2.1.2.4 Designing Below a Maximum Current Limit

Some applications require that current limiting must occur below a certain threshold. For this example, assume that 1 A must be delivered to the load so that the minimum desired current-limit threshold is 1000 mA. Use the I_{OS} equations and Figure 13 to select R_{ILIM} .

$$I_{OSmax}(mA) = 1000 mA$$

$$I_{OSmax}(mA) = \frac{49497}{R_{(ILIM)}^{0.933} k\Omega} - 37$$

$$R_{(ILIM)}(k\Omega) = \left(\frac{49497}{I_{OS(max)}}\right)^{\frac{1}{0.933}} = \left(\frac{49497}{1000 + 37}\right)^{\frac{1}{0.933}} = 63k\Omega$$
(5)

Select the closest 1% resistor greater than the calculated value: $R_{ILIM} = 63.4 \text{ k}\Omega$. This sets the maximum current-limit threshold at 994 A.

$$I_{OSmax}(mA) = \frac{49497}{R_{(ILIM)}^{0.933}k\Omega} - 37 = \frac{49497}{(63.4)^{0.933}} - 37 = 994 \text{ mA}$$
(6)

Use the I_{OS} equations, Figure 13, and the previously calculated value for R_{ILIM} to calculate the minimum resulting current-limit threshold at 778 mA.

$$I_{OSmin}(mA) = \frac{50576}{R_{(ILIM)}^{0.987}} - 64 = \frac{50576}{(63.4)^{0.987}} - 64 = 778 \text{ mA}$$
(7)

10.2.1.2.5 Accounting for Resistor Tolerance

The previous sections described the selection of $R_{\rm ILIM}$ given certain application requirements and the importance of understanding the current-limit threshold tolerance. The analysis focused only on the TPS2561A-Q1 performance and assumed an exact resistor value. However, resistors sold in quantity are not exact and are bounded by an upper and lower tolerance centered around a nominal resistance. The additional $R_{\rm ILIM}$ resistance tolerance directly affects the current-limit threshold accuracy at a system level. The following table shows a process that accounts for worst-case resistor tolerance assuming 1% resistor values. Step one follows the selection process outlined in the application examples above. Step two determines the upper and lower resistance bounds of the selected resistor. Step three uses the upper and lower resistor bounds in the $I_{\rm OS}$ equations to calculate the threshold limits. It is important to use tighter tolerance resistors, that is, 0.5% or 0.1%, when precision current limiting is desired.

Table 2. Common R_{ILIM} Resistor Selections

Desired			Resistor	Tolerance	Actual Limits			
Nominal Current Limit (mA)	t Limit (kΩ)		1% low (kΩ)	1% high (kΩ)	IOS MIN (mA)	IOS Nom (mA)	IOS MAX (mA)	
300	187.5	187	185.1	188.9	223	301	342	
550	101.6	102	101.0	103.0	457	548	631	
800	69.5	69.8	69.1	70.5	694	797	914	
1050	52.8	52.3	51.8	52.8	944	1060	1208	
1300	42.6	42.2	41.8	42.6	1182	1311	1484	
1550	35.6	35.7	35.3	36.1	1406	1547	1741	
1800	30.6	30.9	30.6	31.2	1631	1784	1998	
2050	26.9	26.7	26.4	27.0	1894	2062	2295	
2300	23.9	23.7	23.5	23.9	2138	2320	2569	
2550	21.5	21.5	21.3	21.7	2360	2554	2817	
2800	19.6	19.6	19.4	19.8	2592	2799	3075	



10.2.1.2.6 Power Dissipation and Junction Temperature

The low on-resistance of the N-channel MOSFET allows small surface-mount packages to pass large currents. It is good design practice to estimate power dissipation and junction temperature. The below analysis gives an approximation for calculating junction temperature based on the power dissipation in the package. However, it is important to note that thermal analysis is strongly dependent on additional system level factors. Such factors include air flow, board layout, copper thickness and surface area, and proximity to other devices dissipating power. Good thermal design practice must include all system level factors in addition to individual component analysis.

Begin by determining the $r_{DS(on)}$ of the N-channel MOSFET relative to the input voltage and operating temperature. As an initial estimate, use the highest operating ambient temperature of interest and read $R_{DS(on)}$ from the typical characteristics graph. Using this value, the power dissipation can be calculated by:

$$P_D = (R_{DS(on)} \times I_{OUT1}^2) + (R_{DS(on)} \times I_{OUT2}^2)$$

Where:

 P_D = Total power dissipation (W)

 $r_{DS(on)}$ = Power switch on-resistance of one channel (Ω)

 I_{OUTx} = Maximum current-limit threshold set by $R_{ILIM}(A)$

This step calculates the total power dissipation of the N-channel MOSFET.

Finally, calculate the junction temperature:

$$T_J = P_D \times \theta_{JA} + T_A$$

Where:

 T_A = Ambient temperature (°C)

 θ_{JA} = Thermal resistance (°C/W)

P_D = Total power dissipation (W)

Compare the calculated junction temperature with the initial estimate. If they are not within a few degrees, repeat the calculation using the "refined" $R_{DS(on)}$ from the previous calculation as the new estimate. Two or three iterations are generally sufficient to achieve the desired result. The final junction temperature is highly dependent on thermal resistance θ_{JA} , and thermal resistance is highly dependent on the individual package and board layout. The Thermal Characteristics Table provides example thermal resistances for specific packages and board layouts.



10.2.1.2.7 Auto-Retry Functionality

Some applications require that an overcurrent condition disables the part momentarily during a fault condition and re-enables after a pre-set time. This auto-retry functionality can be implemented with an external resistor and capacitor. During a fault condition, FAULTx pulls ENx low disabling the part. The part is disabled when ENx is pulled below the turn-off threshold, and FAULTx goes high impedance allowing C_{RETRY} to begin charging. The part re-enables when the voltage on ENx reaches the turn-on threshold, and the auto-retry time is determined by the resistor, capacitor time constant. The part will continue to cycle in this manner until the fault condition is removed.

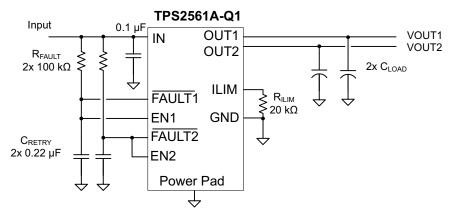


Figure 14. Auto-Retry Functionality

Some applications require auto-retry functionality and the ability to enable/disable with an external logic signal. The figure below shows how an external logic signal can drive EN through R_{FAULT} and maintain auto-retry functionality. The resistor/capacitor time constant determines the auto-retry time-out period.

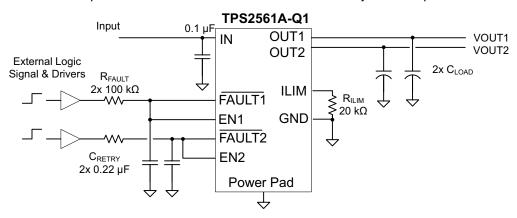


Figure 15. Auto-Retry Functionality With External EN Signal



10.2.1.2.8 Two-Level Current-Limit Circuit

Some applications require different current-limit thresholds depending on external system conditions. Figure 16 shows an implementation for an externally controlled, two-level current-limit circuit. The current-limit threshold is set by the total resistance from ILIM to GND (see previously discussed *Programming the Current-Limit Threshold* section). A logic-level input enables/disables MOSFET Q1 and changes the current-limit threshold by modifying the total resistance from ILIM to GND. Additional MOSFET/resistor combinations can be used in parallel to Q1/R2 to increase the number of additional current-limit levels.

NOTE

ILIM should never be driven directly with an external signal.

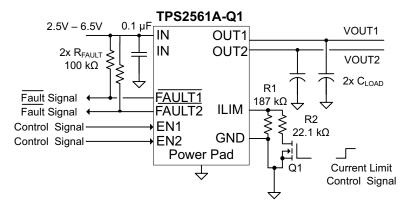
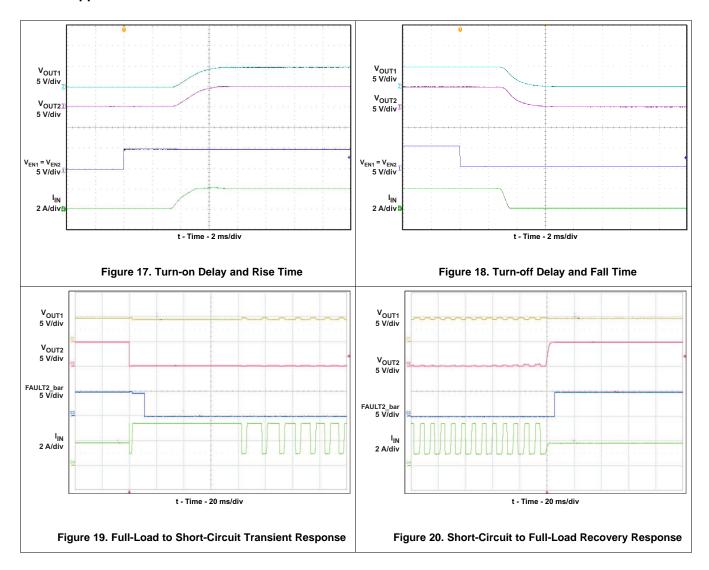


Figure 16. Two-Level Current-Limit Circuit



10.2.2 Application Curves



11 Power Supply Requirements

The device is designed to operate from an input voltage supply range of $2.5\ V$ to $6.5\ V$. The current capability of upper power should exceed the max current limit of the power switch.



12 Layout

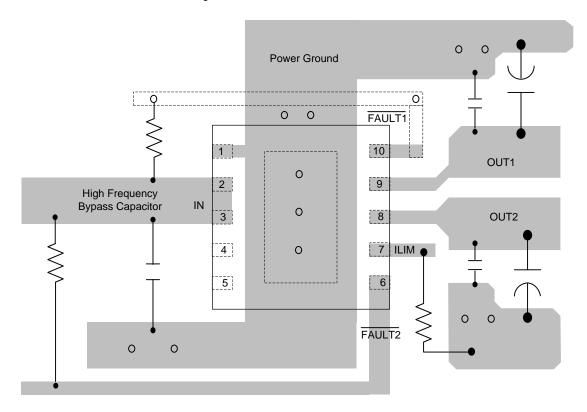
12.1 Layout Guidelines

For all applications, a 0.1-µF or greater ceramic bypass capacitor between IN and GND is recommended as close to the device as possible for local noise decoupling. This precaution reduces ringing on the input due to power-supply transients. Additional input capacitance may be needed on the input to reduce voltage overshoot form exceeding the absolute-maximum voltage of the device during heavy transient conditions.

- Output capacitance is not required, but placing a high-value electrolytic capacitor on the output pin is recommended when large transient currents are expected on the output.
- The traces routing the R_{ILIM} resistor to the device should be as short as possible to reduce parasitic effects on the current limit accuracy.
- The PowerPAD™ should be directly connected to PCB ground plane using wide and short copper trace.

12.2 Layout Example

O VIA to Power Ground Plane





13 器件和文档支持

13.1 商标

PowerPAD is a trademark of Texas Instruments.

13.2 静电放电警告



这些装置包含有限的内置 ESD 保护。 存储或装卸时,应将导线一起截短或将装置放置于导电泡棉中,以防止 MOS 门极遭受静电损伤。

13.3 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms and definitions.

14 机械封装和可订购信息

以下页中包括机械封装和可订购信息。 这些信息是针对指定器件可提供的最新数据。 这些数据会在无通知且不对本文档进行修订的情况下发生改变。 欲获得该数据表的浏览器版本,请查阅左侧的导航栏。

www.ti.com 10-Nov-2025

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
TPS2561AQDRCRQ1	Active	Production	VSON (DRC) 10	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2561AQ
TPS2561AQDRCRQ1.A	Active	Production	VSON (DRC) 10	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2561AQ
TPS2561AQDRCTQ1	Active	Production	VSON (DRC) 10	250 SMALL T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2561AQ
TPS2561AQDRCTQ1.A	Active	Production	VSON (DRC) 10	250 SMALL T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2561AQ

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

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OTHER QUALIFIED VERSIONS OF TPS2561A-Q1:

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE OPTION ADDENDUM

www.ti.com 10-Nov-2025

● Catalog : TPS2561A

NOTE: Qualified Version Definitions:

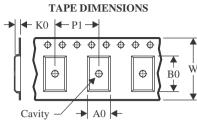
Catalog - TI's standard catalog product

PACKAGE MATERIALS INFORMATION

www.ti.com 20-Apr-2023

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS2561AQDRCRQ1	VSON	DRC	10	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
TPS2561AQDRCTQ1	VSON	DRC	10	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2

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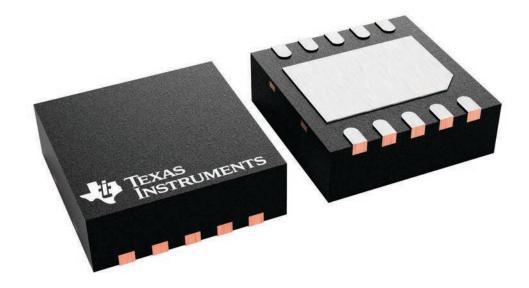
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPS2561AQDRCRQ1	VSON	DRC	10	3000	346.0	346.0	33.0
TPS2561AQDRCTQ1	VSON	DRC	10	250	210.0	185.0	35.0

3 x 3, 0.5 mm pitch

PLASTIC SMALL OUTLINE - NO LEAD

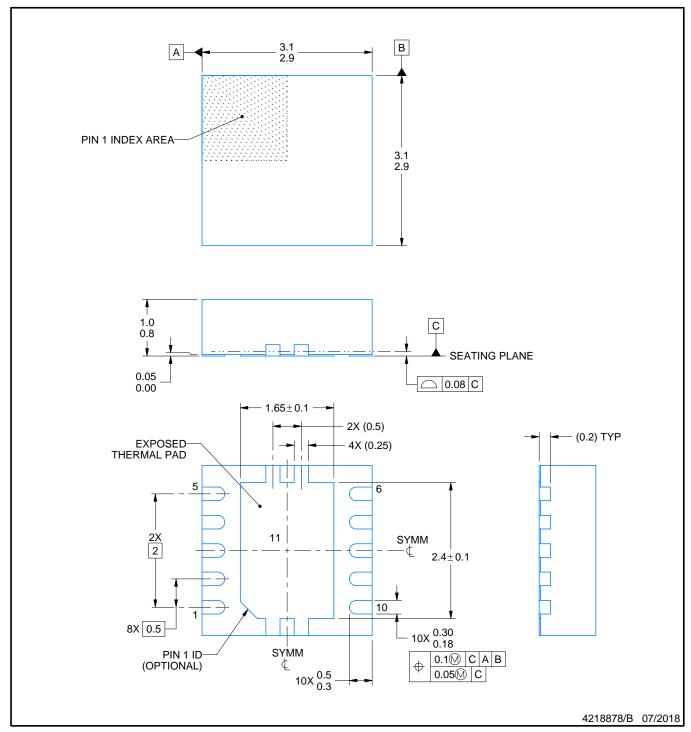
This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



INSTRUMENTS www.ti.com



PLASTIC SMALL OUTLINE - NO LEAD

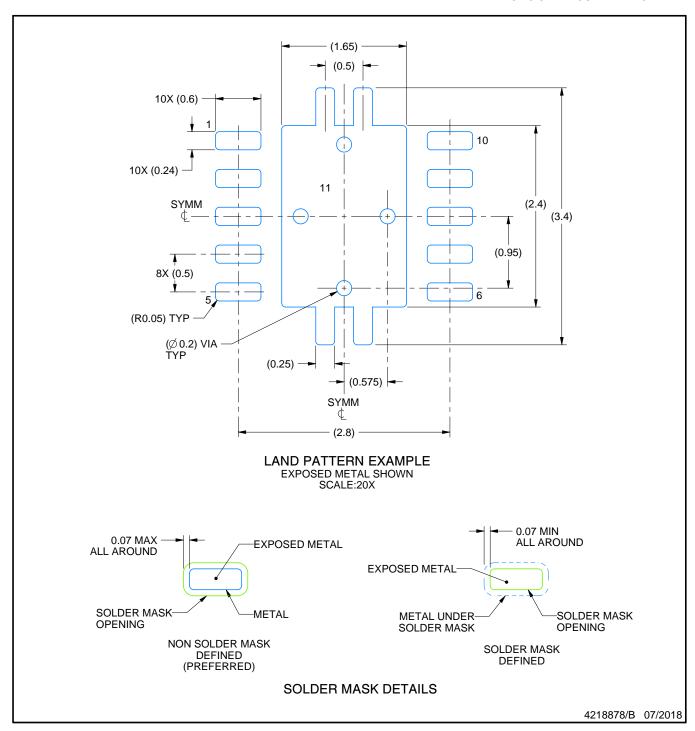


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



PLASTIC SMALL OUTLINE - NO LEAD

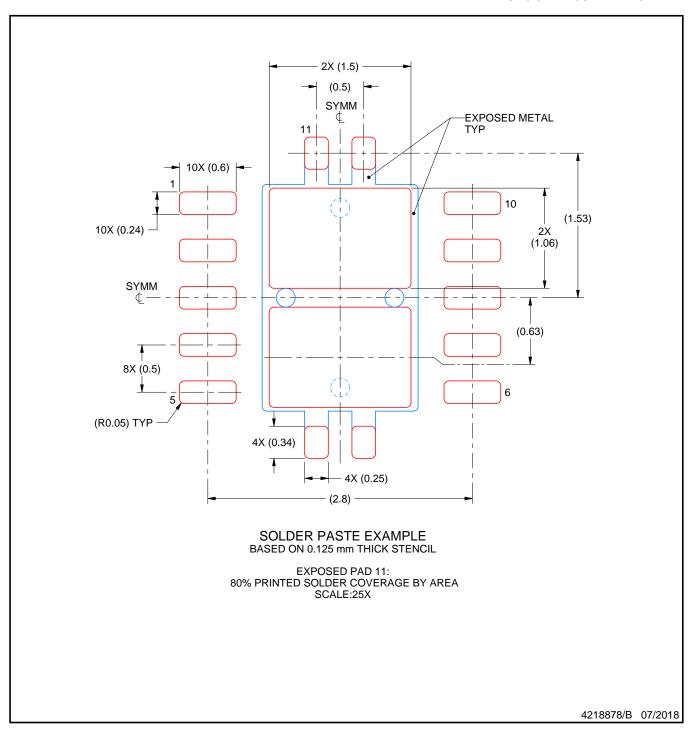


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC SMALL OUTLINE - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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